

<b>Form PTO-1449</b>  <p style="text-align: center;"><b>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE</b></p> <p style="text-align: center;"><b>STATEMENT</b> (Use Several Sheets If Necessary)</p>	<b>ATTY. DOCKET NO.</b> Ons00393	<b>SERIAL NO.</b> <div style="font-size: 1.5em; font-family: cursive;">101615171</div>
<b>APPLICANT</b> Evgueniy Nikolov Stefanov et al		
<b>FILING DATE</b> <b>CONCURRENTLY</b>		<b>GROUP</b> <div style="font-size: 1.5em; font-family: cursive;">2815</div>

**REFERENCE DESIGNATION      U.S. PATENT DOCUMENTS**

Examiner Initial		Document Number								Date	Name	Class	Sub-Class	Filing date (If appropriate)
MELW	AA		5	8	4	4	2	8	0	12/1/1998	Kim	H01L	23/62	
	AB		6	3	2	3	0	7	4	11/27/2001	Jiang et al	H01L	28/8238	
	AC		5	6	0	2	4	0	4	2/11/1997	Chen et al	H01C	31/111	
	AD		6	2	6	8	9	9	2	7/31/2001	Lee et al	H02H	3/22	
	AE		5	9	5	9	8	2	1	8/28/1999	Voogel	H02H	3/22	
	AF		5	7	4	2	0	8	5	4/21/1998	Yu	H01L	23/62	
	AG		5	5	4	1	8	0	1	7/30/1996	Lee et al	H02H	9/04	
	AH		5	4	5	2	1	7	1	9/19/1995	Metz et al	H01L	29/06	
	AI		5	0	7	2	2	7	3	12/10/1991	Avery	H01L	29/72	
	AJ		5	5	7	6	5	5	7	11/19/1996	Ker et al	H01L	29/74	
	AK		5	5	7	2	3	9	4	11/5/1996	Ker et al	H02H	9/00	
	AL	2002	0	1	5	4	4	6	3	10/24/2002	Mergens et al	H02H	9/00	
	AM	2002	0	1	5	3	6	7	1	10/24/2002	Raymond et al	F16L	17/06	

**FOREIGN PATENT DOCUMENTS**

Examiner Initial	Document #	Date	Country	Class/subclass	Translation Yes - No
AN					
AO					
AP					
AQ					
AR					

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

MELW	AS	IEEE Electron Device Letters, Vol 12, No. 1, January 1991, pages 21-22, Chatterjee et al., "A Low-Voltage Triggering SCR for On-Chip ESD Protection at Output and Input Pads"
MELW	AT	IEEE Transactions on Electron Devices, Vol. 43, No. 4, April 1996, pages 588-598, Ker et al., "Complementary-LVTSCR ESD Protection Circuit for Submicron CMOS VLSI/ULSI"
	AU	
	AV	
	AW	

EXAMINER Matthew E. Warner

DATE CONSIDERED 7/21/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.